

## METHOD AND APPARATUS FOR TESTING RF MODULES

### **ABSTRACT:**

A device that has an antenna and an internal RF circuit is connected by an electrical conductor that has a first portion coupled to the RF circuit and an opposed, flexibly resilient second portion. The second portion defines a contact point and a testing point. The contact point is normally electrically coupled to the antenna by a bias in the second portion. When a biasing force such as a RF testing probe exerts force on the testing point through an aperture of a device housing, the normal bias of the second portion is overcome and contact is temporarily interrupted between the antenna and the contact point. The RF probe is placed in electrical contact with the RF circuit by contact with the testing point, which may be directly when a cover over the aperture is removable, or via a conductive pathway imposed through a flexible membrane that is fixed to the housing as a cover over the aperture.